



Single Event Burnout voltage dependence on sensor thickness. The minimum  $V_{SEB}$  at which SEB was observed after several  $10^6$  particles/pad for each thickness in 2021 HGTD End-Of-Lifetime Test beams is shown (manufacturer-run (type, test-beam)). About 80 sensors (single-pad, 2x2, 5x5 arrays) were tested. Note that 55  $\mu\text{m}$  thick device survived at indicated voltage. The line fit to the points results in critical average electric field of  $12.1 \text{ V}/\mu\text{m}$  where SEB occur. The safe zone of  $11 \text{ V}/\mu\text{m}$  where no SEB was ever observed is indicated in yellow.